## DEPARTMENT OF METALLURGICAL AND MATERIALS ENGINEERING NATIONAL INSTITUTE OF TECHNOLOGY: TIRUCHIRAPPALLI - 620 015

27.12.2013

## Minutes of the Pre-Bid conference

## Tender Notification No.: NITT /F.NO: 003/UG LAB MODERNISATION/PLAN 2013-2014/MME

The pre-bid conference was held on 27.12.2013 at 3.00 pm. in the committee room of MME to discuss the specification published in the tender. All other terms and conditions mentioned in the tender document remains same.

Based on the discussion, the committee recommends the following amendments to the specification.

Specification for Tribo Corrosion Facility

Original tender specification		Amended specification
TEM	SPECIFICATIONS	
Contact configuration	Ball on plate (point contact) Pin on plate (area contact)	No amendment
Ball holder size	6 -12mm	No amendment
Pin holder size	6 -12mm	No amendment
Disc diameter	50-100mm	No amendment
Wear track diameter	20-90mm	No amendment
Normal Load range	0.5 - 200N	No amendment
Disc rotation speed	1-3000 rpm	For upper sample , bottom sample stationary to prevent spillage
Frictional force	+200N to -200 N with LC of 0.1N	No amendment
Wear profile measurement	0 to 2000 μm Least count 1μm	No amendment
Oscillatory movement	Amplitude and frequency should be programmable	No amendment
Oscillatory load frequency	1-80Hz	No amendment
High speed online data acquisition system for	friction force, co-efficient of friction, Normal Load	No amendment
Test duration	0 - 99 Hours	No amendment
Power	230V/5A/1P/50Hz	No amendment
Features	<ul> <li>Repeatable dynamic friction measurements, easy to calibrate</li> <li>fully computer controlled and online real time data acquisition system with ups and All in one color laser Printer should be provide along with equipment as default attachments</li> <li>Structure should be rigid and vibrations maintained to minimum. Structure should be standalone bench top system.</li> <li>Lubrication bath for friction and wear test</li> <li>The equipment should be synchronized with an Electrochemical Workstation for measuring corrosion, to be isolated from the rest of system electrically, leads from</li> </ul>	And Electric isolation of disc and pin with rest of the system

Specification for the Electrochemical System  Current: 2Amps Should be able to operate Techniques, Built in Frequency ResponElS measurements in the with selectable amplitude USB controlled system/ s Windows 7 or windows x experiments and analyse: Software techniques Req	d platinum grid to be placed at a in the corrosive medium to act as Provision to make to place saturated to be placed in contact with the foorrosion and wear to be immersed ium and electrically isolated with each subjected to corrosion medium should lean and fix it back as the test is over. rkstation can be procured by the etheir firm.  If Ball Pins and Plates to be provides like surface roughness and hardness used are WC, SiC, Al <sub>2</sub> O <sub>3</sub> , YSZ etc  disc rotatory oscillation and other	Two sets of graphite electrode rods to be placed at two different distances two graphite electrodes per set.  And Sleeve should be leak proof to avoid spillage of corrosion medium and to reduce the noise and electrochemical output.  Additional 1 thermocouple for bottom sample along with electrode  Sample size of Ball/Pin are: 6mm, 8mm,10mm& 12mm of WC, SiC, Al <sub>2</sub> O <sub>3</sub> , YS each 5 nos.  Disc diameter of 100mm made of SS -10Nos & WC- 10Nos.to be provide along the regular equipment  Additional set of the above to be quoted as optional accessories.  And Jigs to be provided to prepare electrochemically isolated test specimen for different wear track diameter.
	erate and perform both AC/DC esponse Analyzer (FRA) for performing the frequency range of 10uHz-1MHz itudes from 0.1mV-1000mV m/ software for 32-bit/ 64 bit ws xp program for electrochemical lyses. Required: , Corrosion, Galvano static, Potentio-Galvano /,Multiple CV,CA,CC,CP,Pulse	<ul> <li>Compliance Voltage: ±12 V at 2A current</li> <li>Current resolution 10pA or better</li> <li>Applied voltage resolution -500nV or better</li> <li>Option to measure external device voltage up to ±10 V</li> <li>Additional 1 thermocouple for bottom sample.</li> <li>Suitable data acquisition system to be provided.</li> <li>CV, SWV, Multiple CV, CA, CC, CP, Pulse Voltammetry, NPV, DPV, RNPV techniques not required.</li> <li>Should quote for 5 years AMC</li> </ul>

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